



Lecture 06 Point Feature Detection and Matching Part 2

Davide Scaramuzza

Mini-project

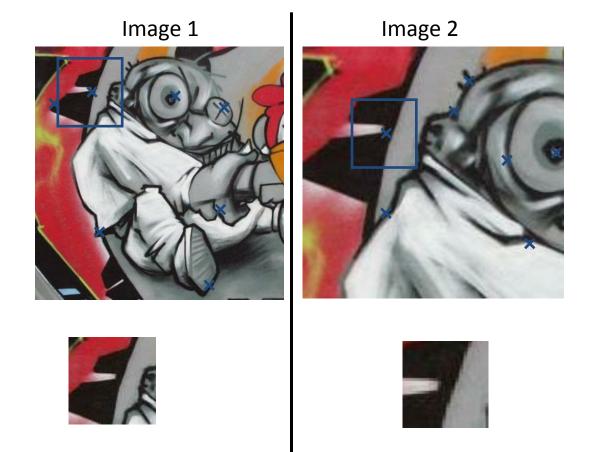
Goal: implement a Visual Odometry (VO) pipeline

- Groups: 1 to 4 students
- Hand-in:
 - Code (Matlab, or alternatively runnable on Ubuntu 14.04)
 - Report (free-form, 5 pages max)
- Goal of report: show us what work you did, what failed and what worked...

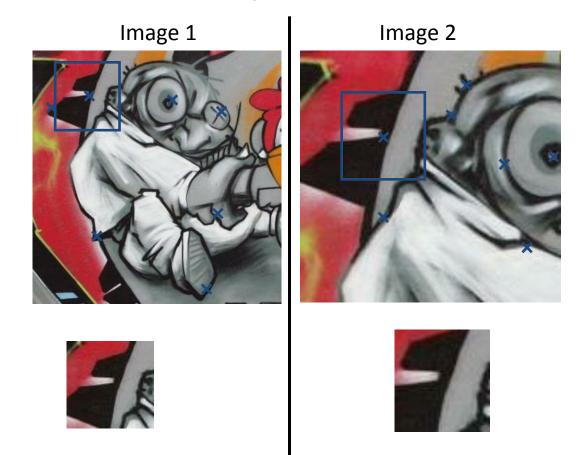
Grading:

- 4.5-5.5: working VO pipeline (grade depends on accuracy)
- 5.5-6: working VO pipeline with extra features (not covered during the exercises)
- < 4.5: pipelines that don't work. The grade will be based on the report.

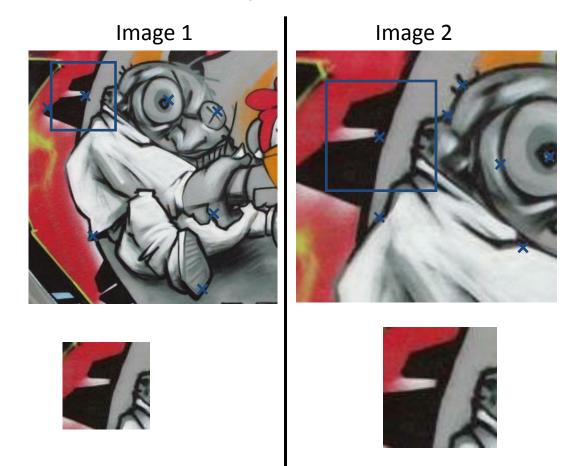
- How can we match image patches corresponding to the same feature but belonging to images taken at different scales?
 - Possible solution: rescale the patch!



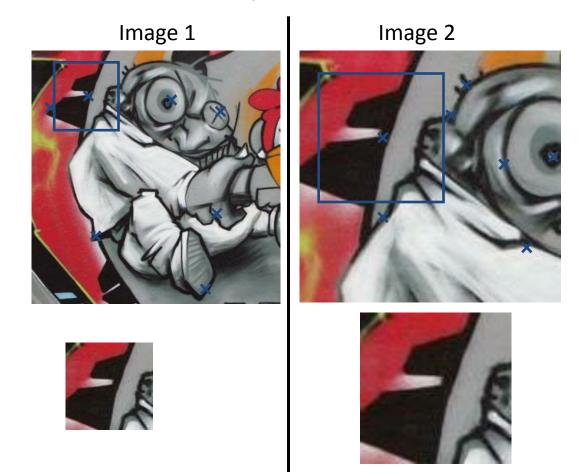
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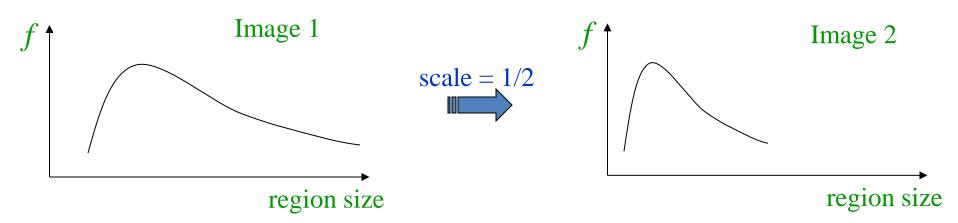
- Scale search is time consuming (needs to be done individually for all patches in one image)
 - Complexity would be $(NM)^2$ (assuming that we have N features per image and M scale levels for each image)
- Possible solution: assign each feature its own "scale" (i.e., size).
 - What's the optimal scale (i.e., size) of the patch?

Solution:

 Design a function on the image patch, which is "scale invariant" (i.e., which has the same value for corresponding regions, even if they are at different scales)

Can this function be the Cornerness Response function? Answer: no! Why? What kind of behavior does it have?

 For a point in one image, we can consider it as a function of region size (patch width)

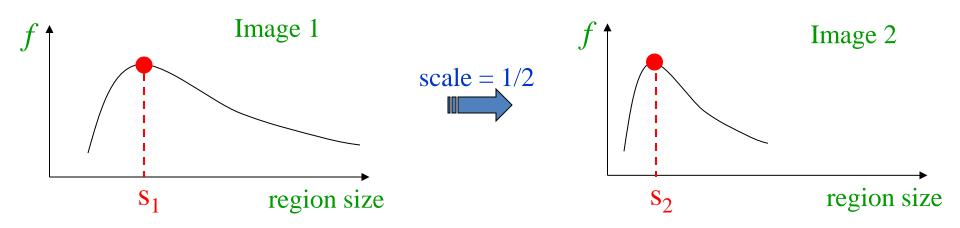


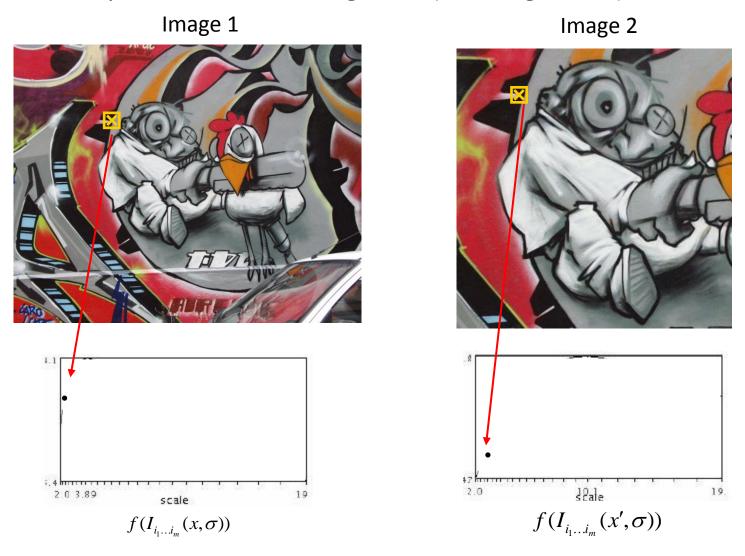
Common approach:

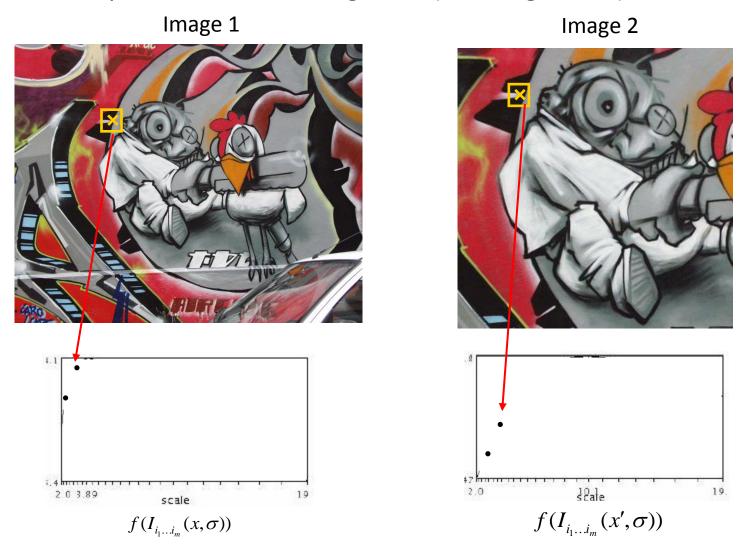
Take a local maximum of this function

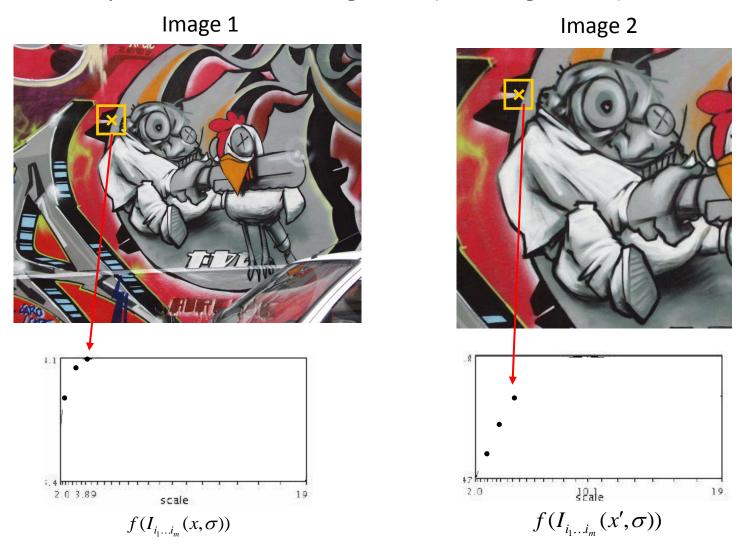
Observation: region size, for which the maximum is achieved, should be *invariant* to image scale.

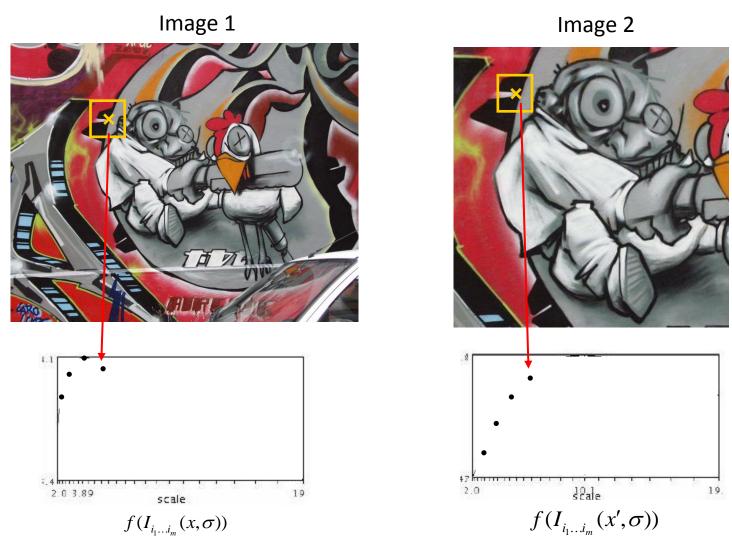
Important: this scale invariant region size is found in each image independently!

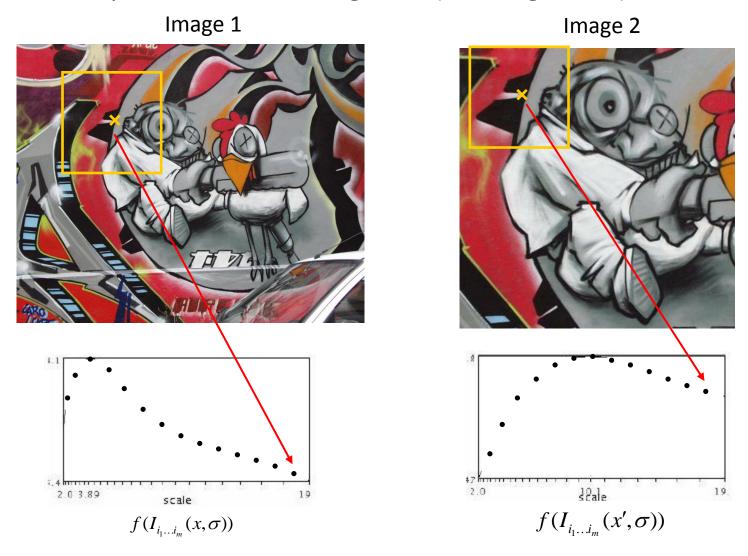


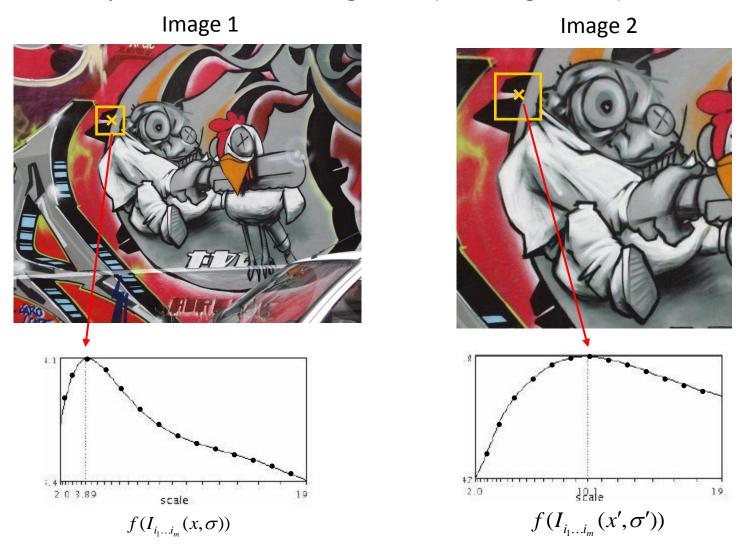




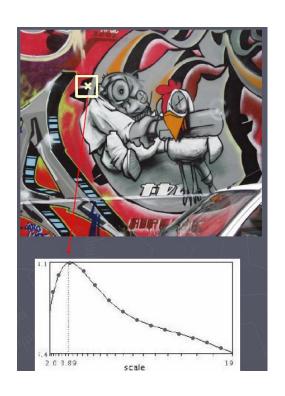


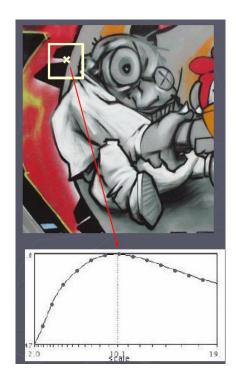


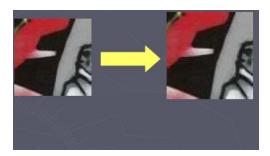


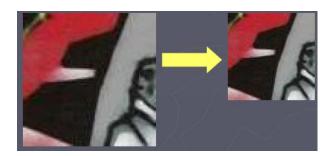


When the right scale is found, the patch must be normalized



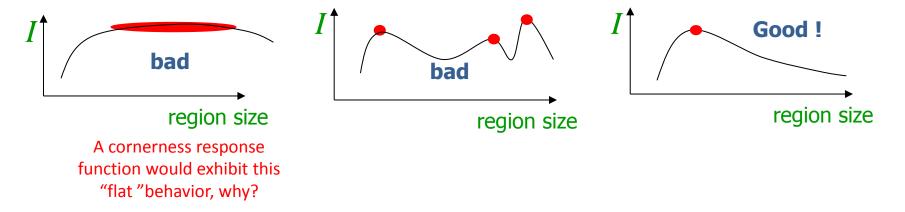






Scale Invariant Detection: Robustness

A "good" function for scale detection should have a single & sharp peak



- Sharp, local intensity changes are good regions to monitor in order to identify the scale
 - ⇒ Blobs and corners are the ideal locations!

Scale Invariant Detection

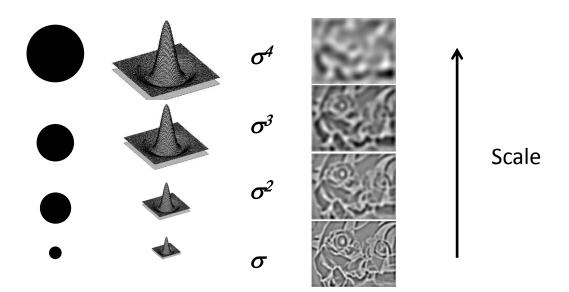
 Functions for determining scale: convolve image with kernel to identify sharp intensity discontinuities

$$f = Kernel * Image$$

Laplacian of Gaussian kernel:

$$LoG = \nabla^2 G(x, y) = \frac{\partial^2 G(x, y)}{\partial x^2} + \frac{\partial^2 G(x, y)}{\partial y^2}$$

Correct scale is found as local maxima across consecutive smoothed images



Scale Invariant Detection

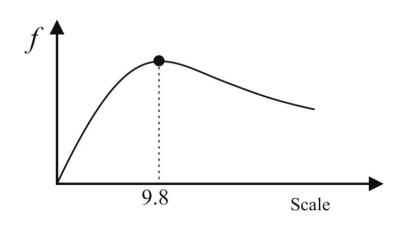
 Functions for determining scale: convolve image with kernel to identify sharp intensity discontinuities

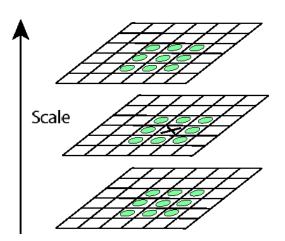
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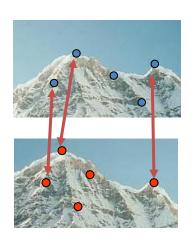
Scale Invariant Detectors

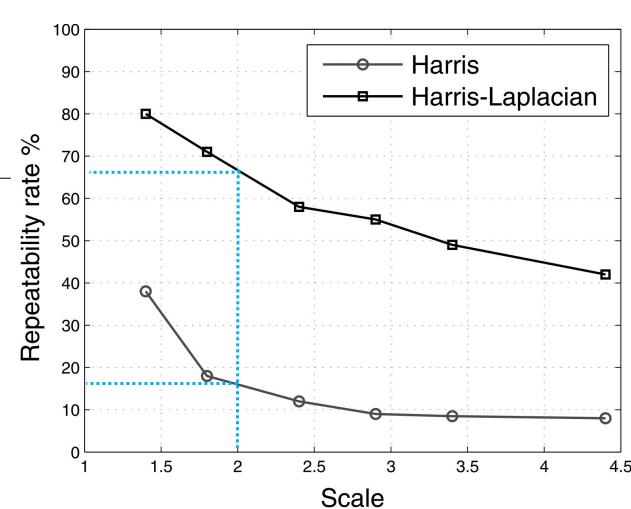
 Experimental evaluation of detectors w.r.t. scale change

Repeatability=

correspondences detected

correspondences present





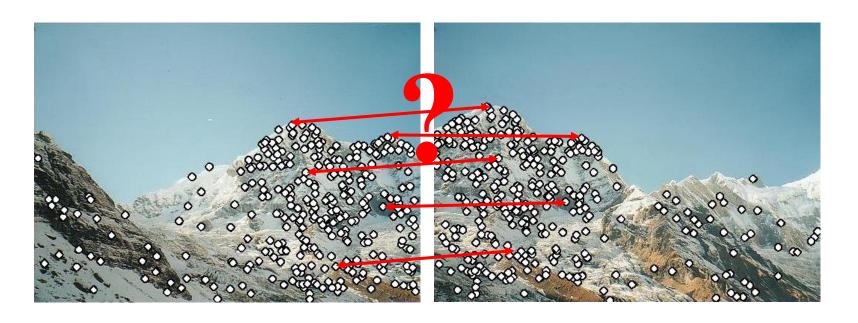
Main questions

- Where will the interest points come from?
 - What are salient features that we'll detect in multiple views?
- How to describe a local region?
- How to establish correspondences, i.e., compute matches?

Feature descriptors

- We know how to detect points
- Next question:

How to *describe* them for matching?



- Simplest descriptor: intensity values within a squared patch or gradient histogram
- Alternative: Histograms of Oriented Gradients (like in SIFT, see later)
- Then, descriptor matching can be done using (Z)SSD, (Z)SAD, or (Z)NCC

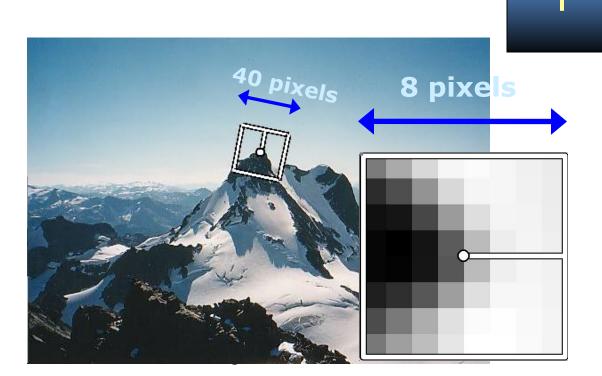
Feature descriptors

- We'd like to find the same features regardless of the transformation (rotation, scale, view point, and illumination)
 - Most feature methods are designed to be invariant to
 - translation,
 - 2D rotation,
 - scale
 - Some of them can also handle
 - Small view-point invariance (3D rotation) (e.g., SIFT works up to about 60 degrees)
 - Linear illumination changes

How to achieve invariance

Step 1: Re-scaling and De-rotation

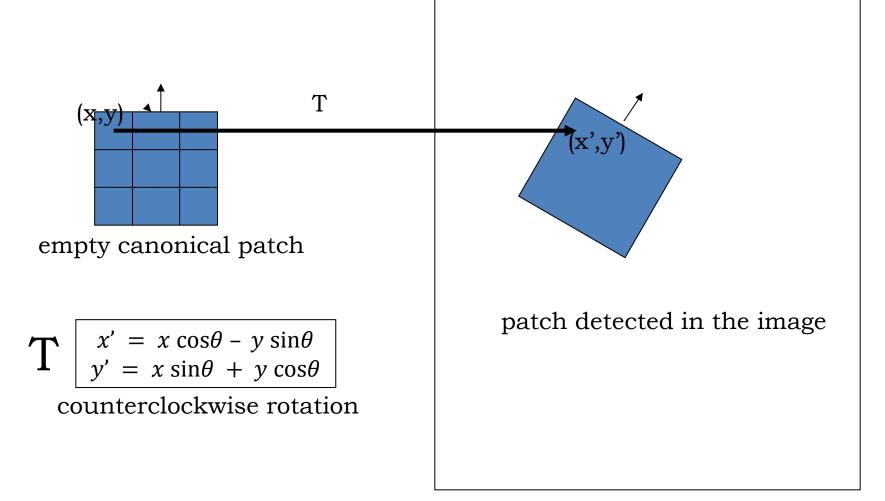
- Find correct scale using LoG operator
- Rescale the patch to a default size (e.g., 8x8 pixels)
- Find local orientation
 - Dominant direction of gradient for the image patch (e.g., Harris eigenvectors)
- De-rotate patch
 - This puts the patches into a canonical orientation



Implementation Concern: How do you rotate a patch?

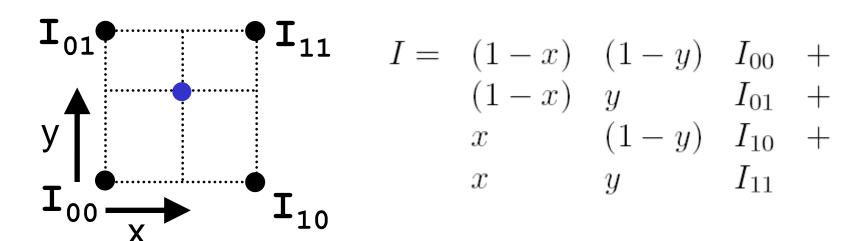
- Start with an "empty" patch whose dominant direction is "up".
- For each pixel in your patch, compute the position in the detected image patch. It will be in floating point and will fall between the image pixels.
- Interpolate the values of the 4 closest pixels in the image, to get a value for the pixel in your patch.

Rotating a Patch



Using Bilinear Interpolation

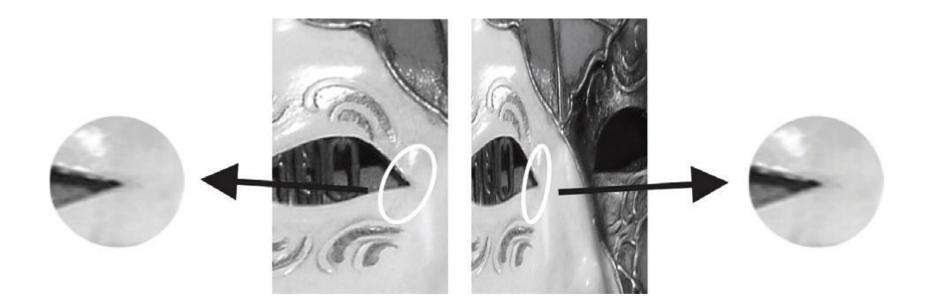
Use all 4 adjacent samples



How to achieve invariance

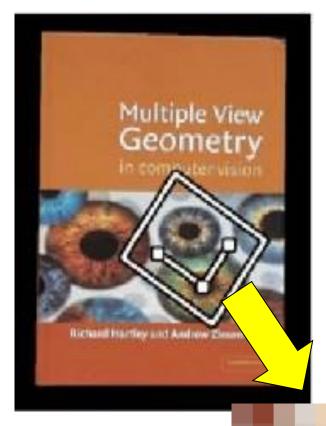
Step 2: Affine Un-warping (to achieve slight view-point invariance)

- The second moment matrix *M* can be used to identify the two directions of fastest and slowest change of intensity around the feature.
- Out of these two directions, an elliptic patch is extracted at the scale computed by with the LoG operator.
- The region inside the ellipse is normalized to a circular one

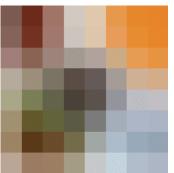


How to achieve invariance

Example: de-rotation, re-scaling, and affine un-warping







Feature descriptors

- Disadvantage of patches as descriptors:
 - Very small errors in rotation, scale, view-point, and illumination can affect matching score significantly
 - Computationally expensive (need to unwarp every patch)

 Better solution today: build descriptors from Histograms of Oriented Gradients (HOGs)

HOG descriptor (Histogram of Oriented Gradients)

- Compute a histogram of orientations of intensity gradients
- Peaks in histogram: dominant orientations
- Keypoint orientation = histogram peak
 - If there are multiple candidate peaks, construct a different keypoint for each such orientation
- Rotate patch according to this angle

Rotation and Scale Normalization

- Rotate the window to standard orientation
- Scale the window size based on the scale at which the point was found.

SIFT descriptor

- Scale Invariant Feature Transform
- Invented by David Lowe [IJCV, 2004]
- Descriptor computation:
 - Divide patch into 4x4 sub-patches: 16 cells
 - Compute histogram of gradient orientations (8 reference angles) for all pixels inside each sub-patch
 - Resulting SIFT descriptor: 4x4x8 = 128 values

Descriptor Matching: Euclidean-distance between these descriptor vectors

(i.e., SSD)

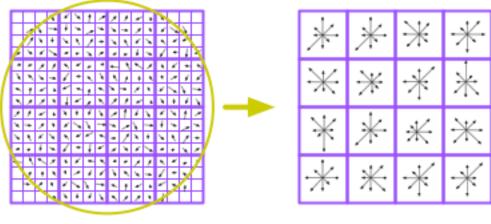


Image gradients

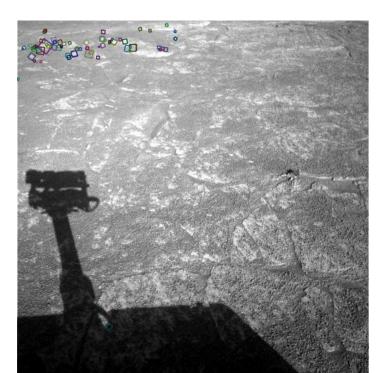
Keypoint descriptor

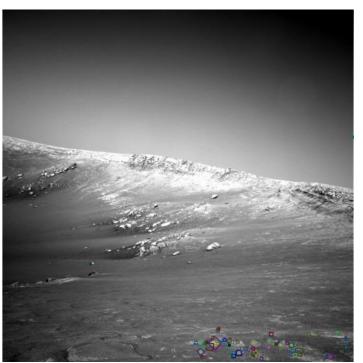
Intensity Normalization

The descriptor values are normalized such that the L2 norm is 1. This
guarantees that the descriptor is invariant to linear illumination changes.

Feature descriptors: SIFT

- Extraordinarily robust matching technique
 - Can handle changes in viewpoint
 - Up to about 60 degree out of plane rotation
 - Can handle significant changes in illumination
 - Sometimes even day vs. night (below)
 - Fast and efficient—can run in real time
 - Original SIFT code (binary files): http://people.cs.ubc.ca/~lowe/keypoints

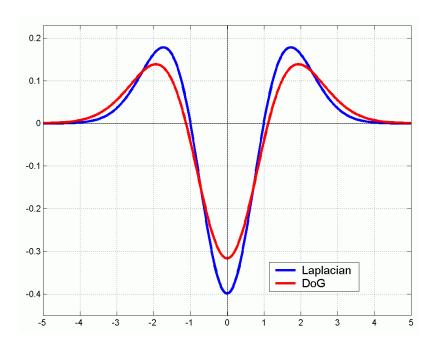




Scale Invariant Detection

Like to Harris Laplacian but Laplacian of Gaussian kernel is approximated with Difference of Gaussian (DoG) kernel (computationally cheaper):

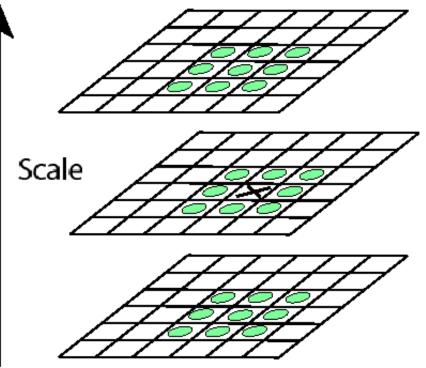
$$LOG \approx DoG = G_{k\sigma}(x, y) - G_{\sigma}(x, y)$$



SIFT detector (location + scale)

SIFT keypoints: local extrema in both location and scale of the DoG

- Detect maxima and minima of difference-of-Gaussian in scale space
- Each point is compared to its 8 neighbors in the current image and 9 neighbors each in the scales above and below



For each max or min found, output is the **location** and the **scale**.





sigma = 2



sigma = 2.5018



sigma = 3.1296



sigma = 3.9149



sigma = 4.8972



sigma = 6.126



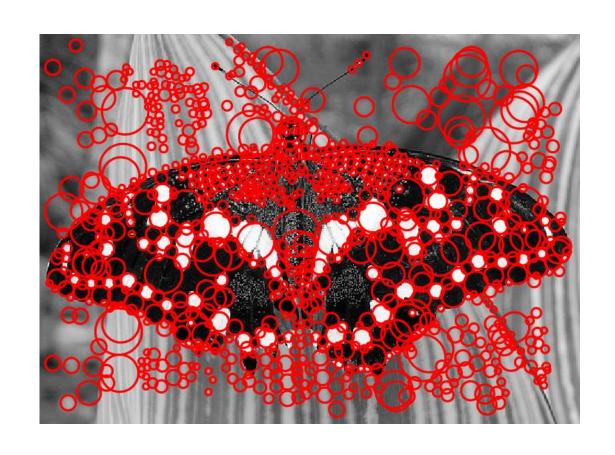
sigma = 7.6631



sigma = 9.5859

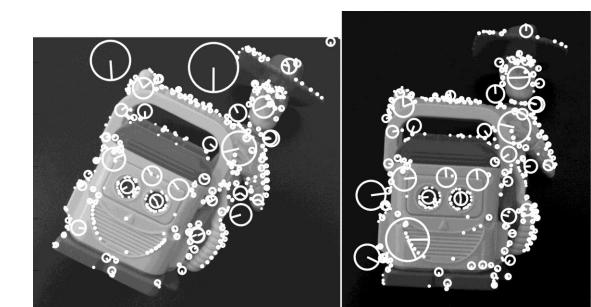


sigma = 11.9912



SIFT Features: Summary

- SIFT: Scale Invariant Feature Transform [Lowe, IJCV 2004]
- An approach to detect and describe regions of interest in an image.
- SIFT features are reasonably invariant to changes in rotation, scaling, and small changes in viewpoint and illumination
- Real-time but still slow (10 Hz on an i7 laptop)
 - > Expensive steps are the scale detection and descriptor extraction

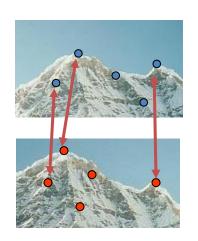


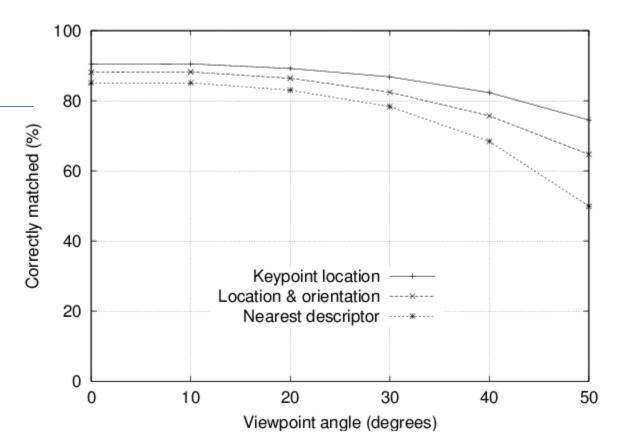
SIFT repeatability vs. viewpoint angle

Repeatability=

correspondences detected

correspondences present



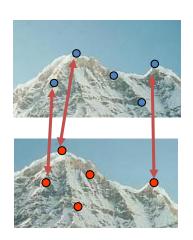


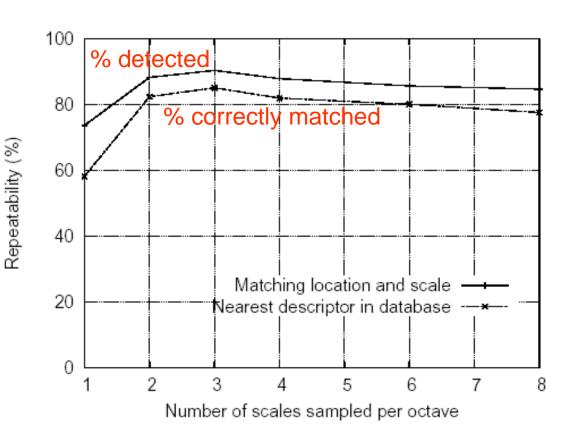
SIFT repeatability vs. Scale

Repeatability=

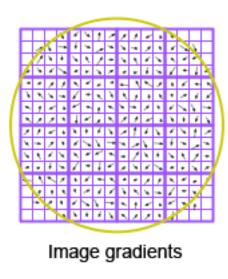
correspondences detected

correspondences present





Influence of Number of Orientations and Sub-patches



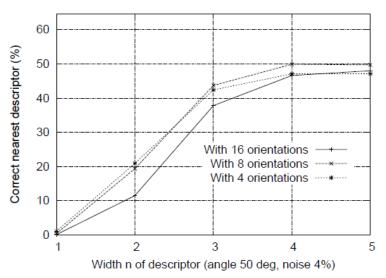
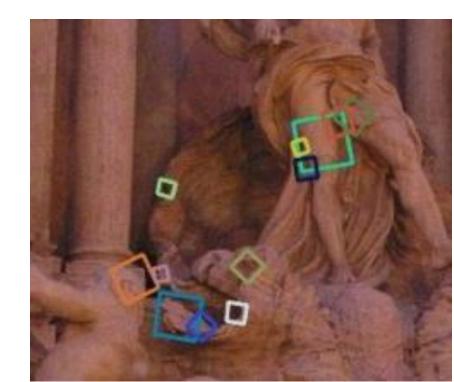


Figure 8: This graph shows the percent of keypoints giving the correct match to a database of 40,000 keypoints as a function of width of the $n \times n$ keypoint descriptor and the number of orientations in each histogram. The graph is computed for images with affine viewpoint change of 50 degrees and addition of 4% noise.

How many parameters are used to define a SIFT feature?

- Descriptor: 128 parameters
- Location (pixel coordinates of the center of the patch): 2D vector
- Scale (i.e., size) of the patch: 1 scalar value
- Orientation (i.e., angle of the patch): 1 scalar value



SIFT for Object recognition





SIFT for Panorama Stitching

AutoStitch: http://matthewalunbrown.com/autostitch/autostitch.html

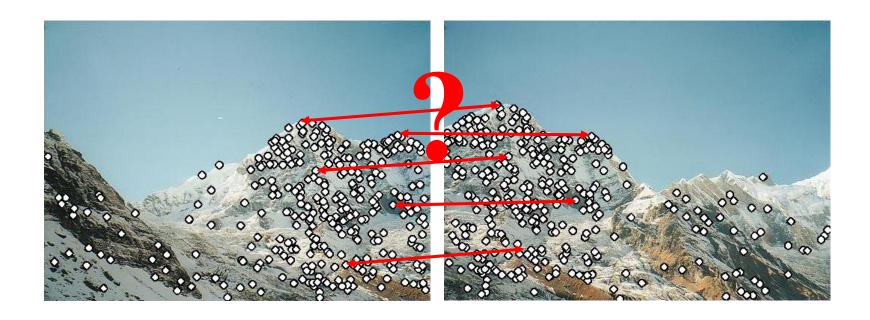
[M. Brown and D. G. Lowe. Recognising Panoramas. ICCV 2003]



Main questions

- Where will the interest points come from?
 - What are salient features that we'll detect in multiple views?
- How to describe a local region?
- How to establish correspondences, i.e., compute matches?

Feature matching



Feature matching

- Given a feature in I_1 , how to find the best match in I_2 ?
 - 1. Define distance function that compares two descriptors
 - SSD
 - SAD
 - NCC
 - 2. Brute-force matching: Test all the features in I_2 , find the one with min distance
- Problem with distance: can give good scores to very ambiguous (bad) matches!
- Better approach: ratio distance = $d(f_1, f_2) / d(f_1, f_2') < Threshold (e.g., 0.8)$
 - f₂ is best match of f₁ in l₂
 - f_2 ' is 2^{nd} best match of f_1 in I_2
 - gives small values for ambiguous matches

SIFT Feature matching: ratio distance

The inventor of the SIFT recommends to use a threshold on 0.8. Where does this come from?

"A threshold of 0.8, eliminates 90% of the false matches while discarding less than 5% of the correct matches."

"This figure was generated by matching images following random scale and orientation change, a depth rotation of 30 degrees, and addition of 2% image noise, against a database of 40,000 keypoints."

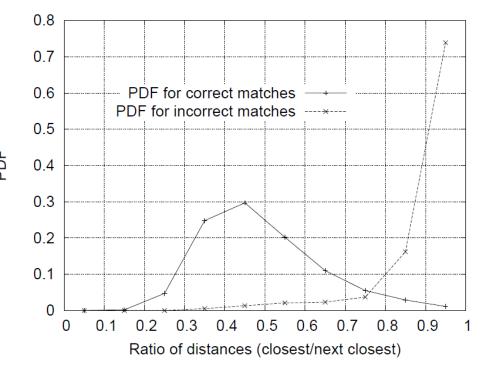


Figure 11: The probability that a match is correct can be determined by taking the ratio of distance from the closest neighbor to the distance of the second closest. Using a database of 40,000 keypoints, the solid line shows the PDF of this ratio for correct matches, while the dotted line is for matches that were incorrect.

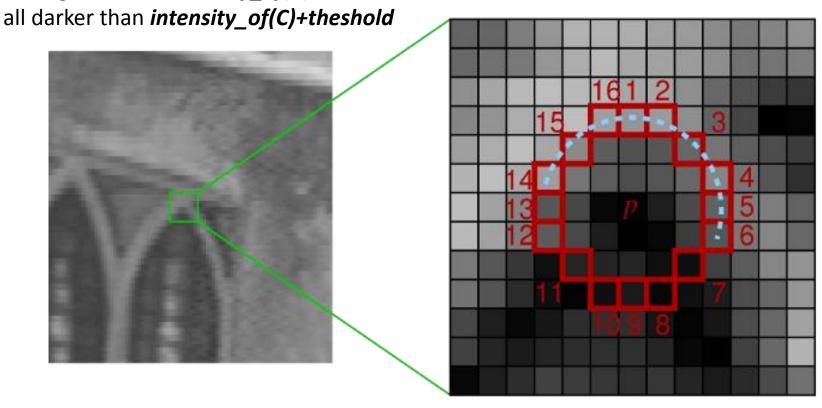
SURF [Bay et al., ECCV 2006]

- Speeded Up Robust Features
- Based on ideas similar to SIFT
- Approximated computation for detection and descriptor
- Results comparable with SIFT, plus:
 - Faster computation
 - Generally shorter descriptors



FAST detector [Rosten et al., ECCV'05]

- FAST: Features from Accelerated Segment Test
- Studies intensity of pixels on circle around candidate pixel C
- **C** is a FAST corner **if** a set of **N** contiguous pixels on circle are:
 - all brighter than intensity_of(C)+theshold, or

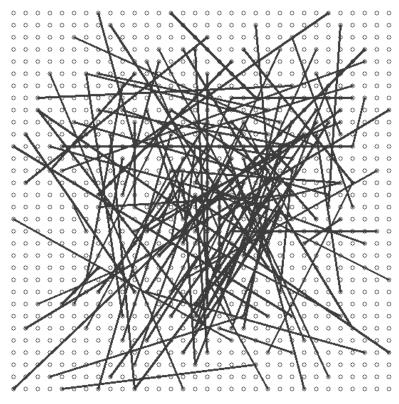


- Typical FAST mask: test for 9 contiguous pixels in a 16-pixel circle
- Very fast detector in the order of 100 Mega-pixel/second

Rosten, Drummond, Fusing points and lines for high performance tracking, IEEE International Conference on Computer Vision, 2005

BRIEF descriptor [Calonder et. al, ECCV 2010]

- Binary Robust Independent Elementary
 Features
- Goal: high speed (in description and matching)
- Binary descriptor formation:
 - Smooth image
 - for each detected keypoint (e.g. FAST),
 - **sample** 256 intensity pairs $\mathbf{p} = (p_1, p_2)$ within a squared patch around the keypoint
 - for each pair p
 - if $I_{p_1} < I_{p_2}$ then **set** bit **p** of descriptor to **1**
 - else set bit p of descriptor to 0
- The pattern is generated randomly only once;
 then, the same pattern is used for all patches
- Not scale/rotation invariant
- Allows very fast Hamming Distance matching: count the number of bits that are different in the descriptors matched



Pattern for intensity pair samples – generated randomly

ORB descriptor

[Rublee et al., ICCV 2011]

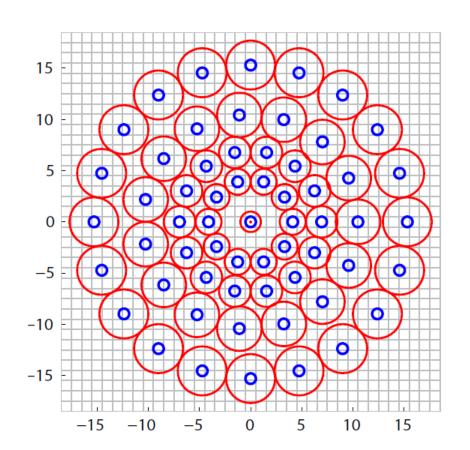
- Oriented FAST and Rotated BRIEF
- Keypoint detector based on FAST
- BRIEF descriptors are steered according to keypoint orientation (to provide rotation invariance)
- Good Binary features are learned by minimizing the correlation on a set of training patches.



BRISK descriptor

[Leutenegger, Chli, Siegwart, ICCV 2011]

- Binary Robust Invariant Scalable Keypoints
- Detect corners in scale-space using FAST
- Rotation and scale invariant
 - Binary, formed by pairwise intensity comparisons (like BRIEF)
 - Pattern defines intensity comparisons in the keypoint neighborhood
 - Red circles: size of the smoothing kernel applied
 - Blue circles: smoothed pixel value used
 - Compare short- and long-distance pairs for orientation assignment & descriptor formation
- Detection and descriptor speed: ~10 times faster than SURF
- Slower than BRIEF, but scale- and rotation- invariant



Recap Table

Detector	Descriptor	Localization Accuracy	Relocalization & Loop closing	Efficiency
Harris	Patch	++++	+	+++
Shi-Tomasi	Patch	++++	+	+++
SIFT	SIFT	+++	++++	+
SURF	SURF	+++	++++	++
FAST	BRIEF ORB BRISK	++++	+++	++++